

# EAST Search History

10/709,729

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	6744	method near test\$4 near (semiconductor\$1 or integrated adj circuit\$1 or die\$1 or dice\$1 or ic\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 14:29
L2	1125	1 and (re\$1test\$4 or test\$4 near (fault\$4 or fail\$4 or defect\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 14:31
L3	44	2 and ((fail\$4 or fault\$4 or defect\$4) near group\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 14:35
L4	39	"5764650"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/08 14:55